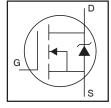


AUIRFB4610 AUIRFS4610

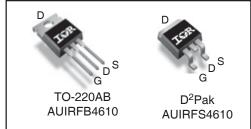
HEXFET® Power MOSFET

Features

- Advanced Process Technology
- Ultra Low On-Resistance
- Enhanced dV/dT and dI/dT capability
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *



V _{(BR)DSS}		100V
R _{DS(on)}	typ.	11m Ω
	max.	14m Ω
I _D		73A



G	D	S					
Gate	Drain	Source					

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T_A) is 25°C, unless otherwise specified.

Parameter	Max.	Units
Continuous Drain Current, V _{GS} @ 10V	73	
Continuous Drain Current, V _{GS} @ 10V	52	Α
Pulsed Drain Current @	290	
Maximum Power Dissipation	190	W
Linear Derating Factor	1.3	W/°C
Gate-to-Source Voltage	± 20	V
Single Pulse Avalanche Energy (Thermally limited) ②	370	mJ
Avalanche Current ①	See Fig. 14, 15, 16a, 16b,	Α
Repetitive Avalanche Energy ①		mJ
Peak Diode Recovery ③	7.6	V/ns
Operating Junction and	-55 to + 175	
Storage Temperature Range		°C
Soldering Temperature, for 10 seconds (1.6mm from case)	300	Ī
Mounting torque, 6-32 or M3 screw	10lbf·in (1.1N·m)	
	Continuous Drain Current, V _{GS} @ 10V Continuous Drain Current, V _{GS} @ 10V Pulsed Drain Current ③ Maximum Power Dissipation Linear Derating Factor Gate-to-Source Voltage Single Pulse Avalanche Energy (Thermally limited) ② Avalanche Current ① Repetitive Avalanche Energy ① Peak Diode Recovery ③ Operating Junction and Storage Temperature Range Soldering Temperature, for 10 seconds (1.6mm from case)	Continuous Drain Current, V _{GS} @ 10V 52 Pulsed Drain Current ④ 290 Maximum Power Dissipation 190 Linear Derating Factor 1.3 Gate-to-Source Voltage ± 20 Single Pulse Avalanche Energy (Thermally limited) ② 370 Avalanche Current ① See Fig. 14, 15, 16a, 16b, Repetitive Avalanche Energy ① 7.6 Operating Junction and 55 to + 175 Storage Temperature Range Soldering Temperature, for 10 seconds (1.6mm from case) 300

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		0.77	
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface , TO-220	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient, TO-220		62]
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) , D ² Pak ⑦		40]

HEXFET® is a registered trademark of International Rectifier.

^{*}Qualification standards can be found at http://www.irf.com/

Static Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.085		V/°C	Reference to 25°C, I _D = 1mA①
R _{DS(on)}	Static Drain-to-Source On-Resistance		11	14	mΩ	V _{GS} = 10V, I _D = 44A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 100 \mu A$
gfs	Forward Transconductance	73			S	$V_{DS} = 50V, I_{D} = 44A$
R_G	Gate Input Resistance		1.5		Ω	f = 1MHz, open drain
I _{DSS}	Drain-to-Source Leakage Current			20		$V_{DS} = 100V, V_{GS} = 0V$
				250	μΑ	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			200	nΛ	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-200	nA	V _{GS} = -20V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

•	• • • • • • • • • • • • • • • • • • • •			-		
	Parameter	Min.	Тур.	Max.	Units	Conditions
Q_g	Total Gate Charge		90	140		$I_D = 44A$
Q_{gs}	Gate-to-Source Charge		20		nC	$V_{DS} = 80V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		36			V _{GS} = 10V ④
t _{d(on)}	Turn-On Delay Time		18			$V_{DD} = 65V$
t _r	Rise Time		87		ا	$I_D = 44A$
t _{d(off)}	Turn-Off Delay Time		53		ns	$R_G = 5.6\Omega$
t _f	Fall Time		70			V _{GS} = 10V ④
C _{iss}	Input Capacitance		3550			$V_{GS} = 0V$
C _{oss}	Output Capacitance		260			$V_{DS} = 50V$
C _{rss}	Reverse Transfer Capacitance		150		pF	f = 1.0MHz, See Fig. 5
C _{oss} eff. (ER)	Effective Output Capacitance (Energy Related)		330			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 80V $ See Fig.11
C _{oss} eff. (TR)	Effective Output Capacitance (Time Related)		380		1	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 80V $

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions	
I _s	Continuous Source Current			73		MOSFET symbol	
	(Body Diode)			73	A	showing the	
I _{SM}	Pulsed Source Current			200	^	integral reverse	
	(Body Diode) ①			290	'	p-n junction diode.	
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 44A, V_{GS} = 0V \oplus$	
t _{rr}	Reverse Recovery Time		35	53	no	$T_J = 25^{\circ}C$ $V_R = 85V$,	
			42	63	ns	$T_J = 125$ °C $I_F = 44A$	
Q _{rr}	Reverse Recovery Charge		44	66	nC	$T_J = 25^{\circ}C$ di/dt = 100A/ μ s \oplus	
			65	98		$T_J = 125$ °C	
I _{RRM}	Reverse Recovery Current		2.1		Α	$T_J = 25^{\circ}C$	
t _{on}	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by T_{Jmax} , starting T_J = 25°C, L = 0.39mH R_G = 25 Ω , I_{AS} = 44A, V_{GS} =10V. Part not recommended for use above this value.
- $\label{eq:loss_def} \ensuremath{\Im} \ I_{SD} \leq 44A, \ di/dt \leq 660A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- 4 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.

- $^{\circ}$ C_{oss} eff. (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- © C_{oss} eff. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- $\ensuremath{\$}\xspace$ R_{θ} is measured at T_J approximately $90^{\circ}C$

Qualification Information[†]

		Automotive			
		(per AEC-Q101) ^{††}			
		Comments: This part number(s) passed Automotive qualification. IR's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.			
Moisture Sensitiv	Moisture Sensitivity Level		N/A		
Moisture Serisiti	vity Level	D ² PAK MSL1			
	Machine Model	Class M4(400V)			
		(per AEC-Q101-002)			
	Human Body Model	Class H1C(2000V)			
ESD		(per AEC-Q101-001)			
	Charged Device		Class C3 (750V)		
	Model	(per AEC-Q101-005)			
RoHS Compliant		Yes			

[†] Qualification standards can be found at International Rectifier's web site: http://www.irf.com/

^{††} Exceptions to AEC-Q101 requirements are noted in the qualification report.

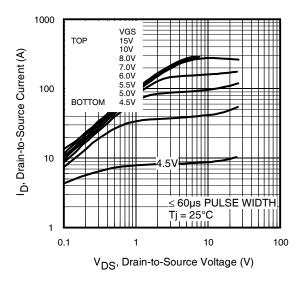


Fig 1. Typical Output Characteristics

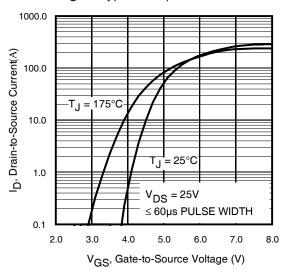


Fig 3. Typical Transfer Characteristics

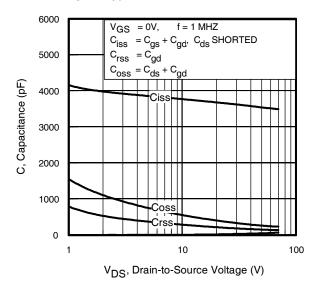


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

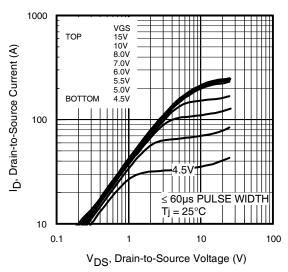


Fig 2. Typical Output Characteristics

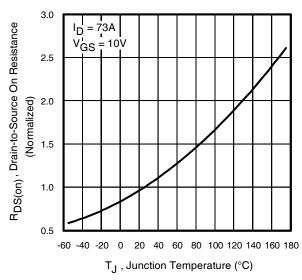


Fig 4. Normalized On-Resistance vs. Temperature

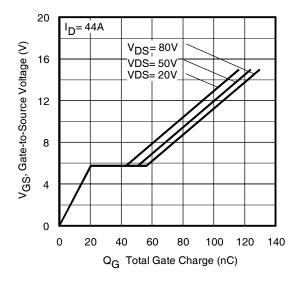


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage www.irf.com

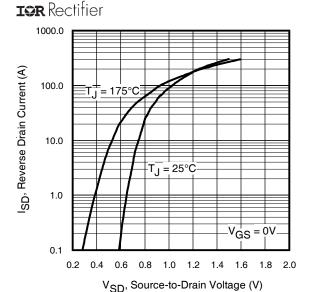


Fig 7. Typical Source-Drain Diode Forward Voltage

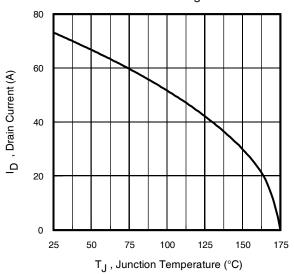


Fig 9. Maximum Drain Current vs. Case Temperature

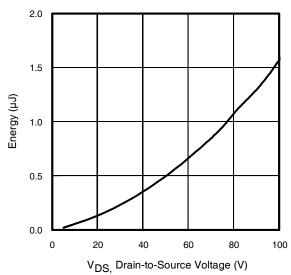


Fig 11. Typical C_{OSS} Stored Energy

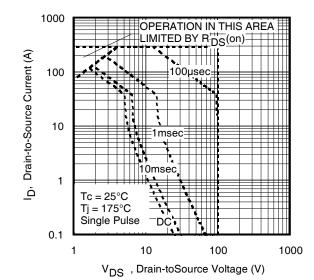


Fig 8. Maximum Safe Operating Area

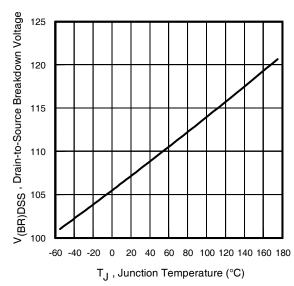


Fig 10. Drain-to-Source Breakdown Voltage

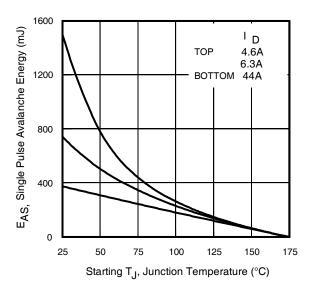


Fig 12. Maximum Avalanche Energy Vs. DrainCurrent

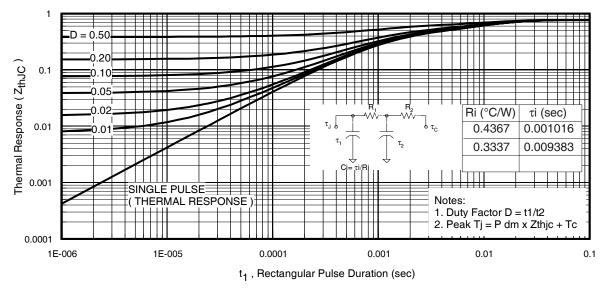


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

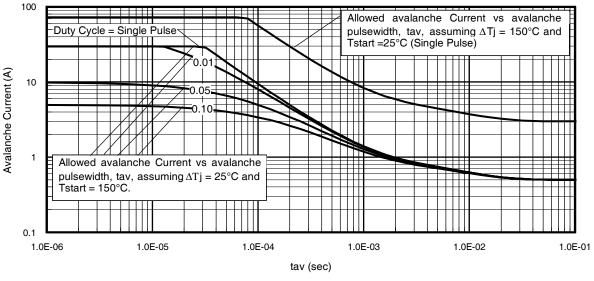


Fig 14. Typical Avalanche Current vs. Pulsewidth

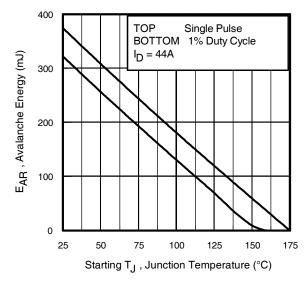


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
- Purely a thermal phenomenon and failure occurs at a temperature far in excess of $T_{\rm jmax}$. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as neither T_{jmax} nor $I_{av\ (max)}$ is exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4. P_{D (ave)} = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).
 - t_{av} = Average time in avalanche.
 - D = Duty cycle in avalanche = tav ·f

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot \text{BV} \cdot \text{I}_{av}) = \triangle \text{T/} \; Z_{thJC} \\ \text{I}_{av} &= 2\triangle \text{T/} \; [1.3 \cdot \text{BV} \cdot Z_{th}] \\ \text{E}_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

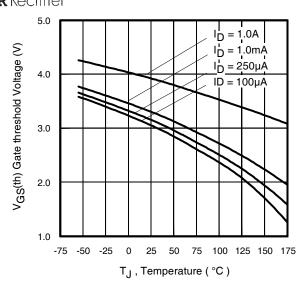


Fig 16. Threshold Voltage Vs. Temperature

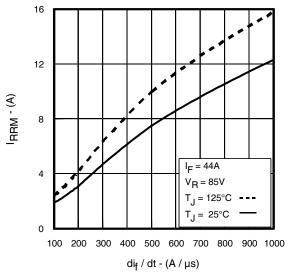


Fig. 18 - Typical Recovery Current vs. dif/dt

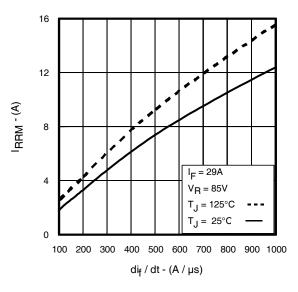


Fig. 17 - Typical Recovery Current vs. di_f/dt

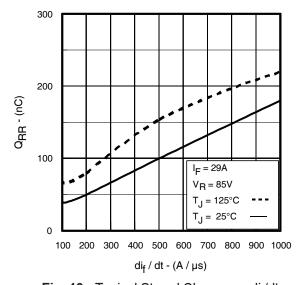


Fig. 19 - Typical Stored Charge vs. di_f/dt

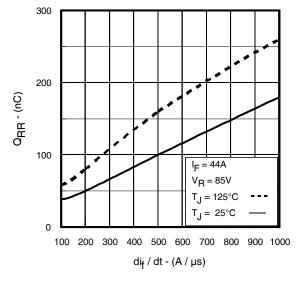


Fig. 20 - Typical Stored Charge vs. dif/dt

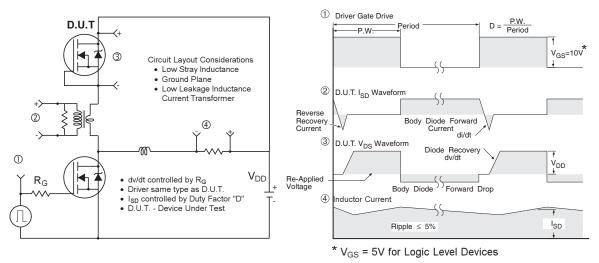


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

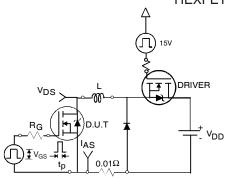


Fig 22a. Unclamped Inductive Test Circuit

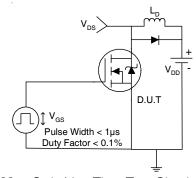


Fig 23a. Switching Time Test Circuit

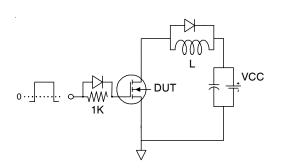


Fig 24a. Gate Charge Test Circuit

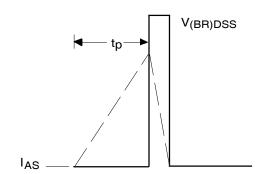


Fig 22b. Unclamped Inductive Waveforms

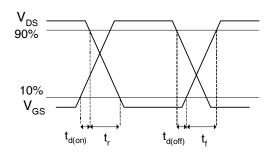


Fig 23b. Switching Time Waveforms

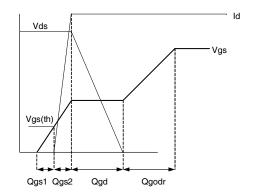


Fig 24b. Gate Charge Waveform

NOTES

5

5

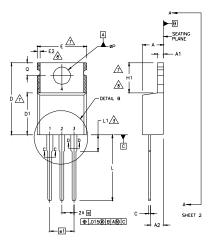
4,7

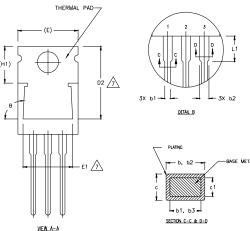
7.8

3

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)





NOTES:

SYMBOL

Α1

A2

ь1

b2

ь3

С

с1

D

D1

D2

E1

е

e1 Н1

1

L1

øΡ

Q

- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS]. LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
- DIMENSION D & E DO NOT INCLUDE MOLD FLASH, WOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION b1 & c1 APPLY TO BASE METAL ONLY. CONTROLLING DIMENSION : INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1

4.82

1,40

2.92

1.01

0.96

1,77

1.73

0.61

0.56

16,51

9.02

12.88

10.66

8.89

6.55

14.73

6.35

4,08

3.42

DIMENSIONS

INCHES

MAX.

.190

.055

.115

.040

.038

.070

.068

.024

.022

.650

.355

.507

.420

.350

.270

.580

.250

.161

.135

MIN.

.140

.020

.080

.015

.015

.045

.045

.014

.014

.560

.330

.480

.380

.330

.230

.500

.139

.100

IPING

5	DIMEN	SIUN	Ł2	Х	н1	DEFINE	A Z(JMF .	MHFKF	STAMPL
	AND	SING	H A	tint	N IF	REGULA	RITIF	S ARI	F ALLOY	₩FD

MILLIMETERS

MIN.

3 56

0.51

2.04

0.38

0.38

1,15

1.15

0.36

0.36

14.22

8.38

12,19

9.66

8.38

5.85

12.70

3.54

2.54

LEAD ASSIGNMENTS

HEXFET

- 1.- GATE 2.- DRAIN 3.- SOURCE

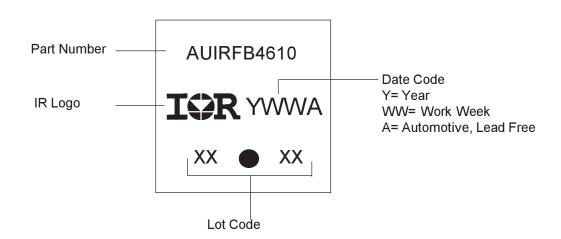
IGBTs, CoPACK

1,- GATE 2,- COLLECTOR 3,- EMITTER

DIODES

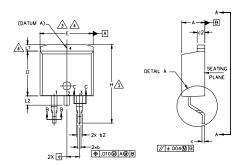
- 1.- ANODE/OPEN 2.- CATHODE 3.- ANODE

TO-220AB	Part	Marking	Information

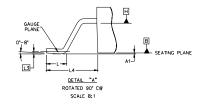


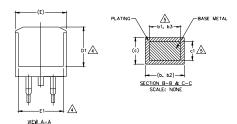


$D^2Pak\ Package\ Outline\ (\ Dimensions\ are\ shown\ in\ millimeters\ (inches))$









UNTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8, OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S	DIMENSIONS						
M B O	MILLIM	IMETERS INCHES			O T E S		
L	MIN.	MAX.	MIN.	MAX.	S		
Α	4.06	4.83	.160	.190			
A1	0.00	0.254	.000	.010			
ь	0.51	0.99	.020	.039			
ь1	0.51	0.89	.020	.035	5		
b2	1.14	1.78	.045	.070			
b3	1.14	1.73	.045	.068	5		
С	0.38	0.74	.015	.029			
c1	0.38	0.58	.015	.023	5		
c2	1.14	1.65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6.86	-	.270		4		
E	9.65	10.67	.380	.420	3,4		
E1	6.22	-	.245		4		
e	2.54	BSC	.100	BSC			
Н	14.61	15.88	.575	.625			
L	1,78	2.79	.070	.110			
L1	-	1.65	-	.066	4		
L2	1.27	1.78	-	.070			
L3	0.25	BSC	.010	BSC			
L4	4.78	5.28	.188	.208			

LEAD ASSIGNMENTS

<u>HEXFET</u>

1.- GATE 2, 4.- DRAIN 3.- SOURCE

IGBTs, CoPACK

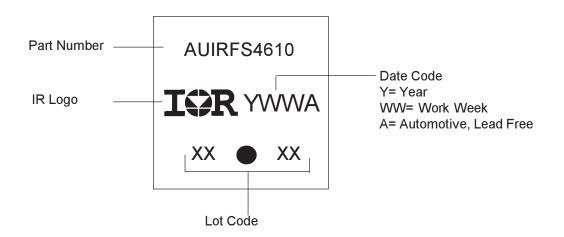
1.- GATE
2, 4.- COLLECTOR
3.- EMITTER

DIODES

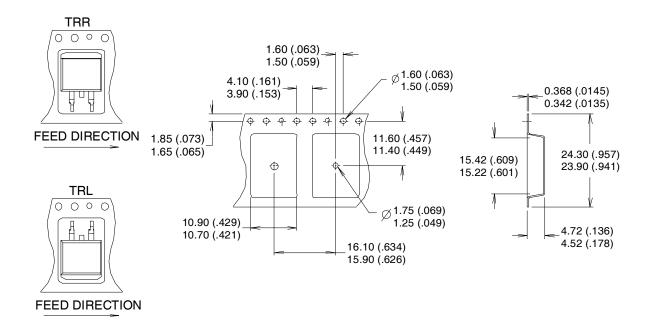
1.- ANODE *
2, 4.- CATHODE
3.- ANODE

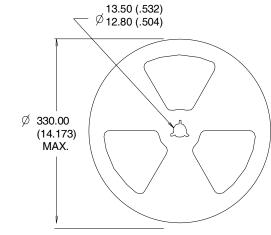
* PART DEPENDENT.

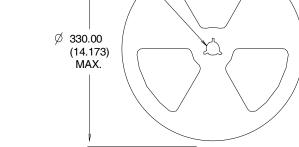
D²Pak Part Marking Information



D²Pak (TO-263AB) Tape & Reel Information

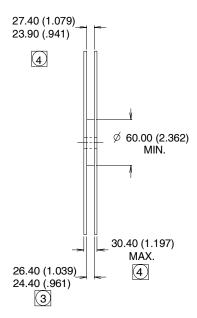






NOTES:

- 1. COMFORMS TO EIA-418.
- CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION MEASURED @ HUB.
- INCLUDES FLANGE DISTORTION @ OUTER EDGE.



Ordering Information

Base part	Package Type	Standard Pack		Complete Part Number
		Form	Quantity	
AUIRFB4610	TO-220	Tube	50	AUIRFB4610
AUIRFS4610	D2Pak	Tube	50	AUIRFS4610
		Tape and Reel Left	800	AUIRFS4610STRL
		Tape and Reel Right	800	AUIRFS4610STRR



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